Locally,

$$\ell = \log \sigma(\mathbf{w} \cdot \tilde{\mathbf{c}}) + k \cdot \mathbb{E}_{c_N \sim p_D(c_N)} \left[\log \sigma(-\mathbf{w} \cdot \tilde{\mathbf{c_N}}) \right]$$

and thus globally

$$\mathcal{L} = \sum_{\mathsf{w} \in \mathsf{V}} \sum_{\mathsf{c} \in \mathsf{V}} (n_{\mathsf{w},\mathsf{c}}) \left(\log \sigma(\mathbf{w} \cdot \tilde{\mathbf{c}}) + k \cdot \mathbb{E}_{\mathsf{c}_N \sim \mathsf{P}_n(\mathsf{c}_N)} \left[\log \sigma(-\mathbf{w} \cdot \tilde{\mathbf{c}_N}) \right] \right)$$

- *k*: number of negative samples to take (hyperparameter)
- $n_{w,c}$: number of times (w, c) was seen in the data
- $\mathbb{E}_{c_N \sim P_n(c_N)}$ indicates an expectation taken with respect to the noise distribution $P_n(c_N)$.